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CONFIRMATION NO. 4653

SERIAL NUMBER 10/628,601		FILING DATE 07/28/2003 RULE	CLASS 438		GROUP ART U 2812	TINL	ATTORNEY DOCKET NO. 31692-73091		
APPLICANTS									
Michael J. Berman, Portland, OR;									
George E. Bailey, Welches, OR; Rennie G. Barber, Gresham, OR;									
** CONTINUING DATA **********************************									
** FOREIGN APPLICATIONS ************************************									
Foreign Priority claims 35 USC 119 (a-d) cor met		yes no	STATE	OR	SHEETS	тот	AL	INDEPENDENT	
					DRAWING 2	1		CLAIMS 1	
ADDRESS LSI Logic Corporation 1551 McCarthy Blvd. Milpitas, CA 95035									
TITLE Method and apparatus for detecting backside contamination during fabrication of a semiconductor wafer									
						□ All Fees			
FILING FEE	FEES	FEES: Authority has been given in Paper Noto charge/credit DEPOSIT ACCOUNT Nofor following:				☐ 1.16 Fees (Filing) ☐ 1.17 Fees (Processing Ext. of			
RECEIVED	No No.					time) 1.18 Fees (Issue)			
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						☐ Credit			